Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/030,032	FICHET ET AL.
Examiner	Art Unit
DANH C. LE	2617

SEARCHED					
Class	Subclass	Date	Examiner		
455	466 412.2 419 414.3	10/12/04	XL.		
348	14.02 455				
380	210				

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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Interference Search		51 06	DCL			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
T 1 11 0 0	1 1			
Inventor Name Search (Chech for double patenting)	1020/04	DCL_		
EAST Search updated	5 3 06	DCL		
EAST Search updated (US USPUB, EPO JPO, DERWENT)	•			
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